

3/17/04

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249791US2S DIV		SERIAL NO. New Divisional Application	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT					
		Hideo ANDO, et al.					
		FILING DATE Herewith		GROUP Unassigned			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
KA	AA	6,212,330-A	04/2001	YAMAMOTO et al.	—	—	
KA	AB	5,991,502	11/1999	KAWAKAMI et al.	—	—	
KA	AC	6,181,870	01/2001	OKADA et al.	—	—	
KA	AD	6,253,026	06/2001	SAEKI et al.	—	—	
KA	AE	6,263,155	07/2001	SAEKI et al.	—	—	
KA	AF	6,347,187	02/2002	SAEKI et al.	—	—	
KA	AG	6,167,189-A	12/2000	TAIRA et al.	—	—	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
KA	AH	JP 11-16824	01/22/99	JAPAN			X
KA	AI	JP 2000-13728	01/14/00	JAPAN			X
KA	AJ	JP 5-74053	03/26/93	JAPAN			X
KA	AK	7-211048	08/11/95	JAPAN			X
KA	AL	JP 8-263969	10/11/96	JAPAN			X
KA	AM	JP 10-289533	10/27/98	JAPAN			X
KA	AN	JP 5-346879	12/27/93	JAPAN			X
KA	AO	JP 9-91878	04/04/97	JAPAN			X
KA	AP	JP 9-23404	01/21/97	JAPAN			X
KA	AQ	JP 9-259572	10/03/97	JAPAN			X
KA	AR	JP 5-81787	04/02/93	JAPAN		X	
KA	AS	JP 11-16286	01/22/99	JAPAN		X	
KA	AT	JP 7-153238	06/16/95	JAPAN			X
KA	AU	JP 9-265733	10/07/97	JAPAN			X
KA	AV	JP 11-215466	08/06/99	JAPAN			X
KA	AW	JP 11-232837	08/27/99	JAPAN			X
KA	AX	JP 11-39800	02/12/99	JAPAN			X
KA	AY	JP 8-339637	12/24/96	JAPAN			X
KA	AZ	WO 98/14938	04/09/98	WIPO (with English Abstract)			
KA	AAA	WO 97/07504	02/27/97	WIPO (with English Abstract)			X
KA	AAB	WO 97/13365	04/10/97	WIPO (with English Abstract)			X
KA	AAC	WO 95/16262	06/15/95	WIPO (with English Abstract)			X
KA	AAD	WO 95/12197	05/04/95	WIPO (with English Abstract)			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
KA	AAE	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-282021 (with English translation)					
KA	AAF	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-260105 (with English translation)					
KA	AAG	Japanese Office Action (Notification of Reasons for Rejection) re: Patent Application JP 8-358546, mailing date: July 30, 2002, mailing no. 250729 (with English translation)					
Examiner <i>Freya Giesen</i>				Date Considered 5/14/06			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

AUG 19 2004

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249791US2SDIV	SHEET 1 OF 1			SERIAL NO. 10/801,701
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT						
		Hideo ANDO, et al.		FILING DATE March 17, 2004			GROUP 2655	
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA							
	AB							
	AC							
	AD							
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
	AM							
	AN							
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		YES	NO
<i>John</i>	AO	6-96559	04/08/1994	JAPAN				X
	AP							
	AQ							
	AR							
	AS							
	AT							
	AU							
	AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW							
	AX							
	AY							
	AZ						<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>They Nguyen</i>		Date Considered <i>5/14/06</i>						

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.